

Specification for

**Harmonized system of
quality assessment for
electronic
components —
Semiconductor
devices —
Integrated circuits:
Digital integrated
circuits —
Blank detail
specification —
MOS ultraviolet light
erasable electrically
programmable
read-only memories**

Committees responsible for this British Standard

The preparation of this British Standard was entrusted to Technical Committee EPL/47 Semiconductors, upon which the following bodies were represented:

- Federation of the Electronics Industry
- GAMBICA (BEAMA Ltd.)
- Ministry of Defence
- Society of British Aerospace Companies Limited

The following bodies were also represented in the drafting of the standard, through subcommittees and panels:

- British Telecommunications Plc
- Federation of the Electronics Industry
- National Supervising Inspectorate (BSI QA)

Amendments issued since publication

Amd. No.	Date	Comments

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National foreword

This British Standard has been prepared under the direction of the Electrotechnical Sector Board. It is identical with IEC Publication 748-2-9 (QC 709106) *Semiconductor devices — Integrated circuits. Part 2: Digital integrated circuits. Section 9: Blank detail specification for MOS ultraviolet light erasable electrically programmable read-only memories*, published by the International Electrotechnical Commission (IEC) and is a harmonized specification within the IECQ system of quality assessment for electronic components.

IEC 748-2-9 was prepared by subcommittee 47A Integrated circuits of Technical Committee No. 47 Semiconductor devices, and the United Kingdom participation in the drafting was provided by Technical Committee EPL/47, Semiconductors.

Scope

This standard lists the test and inspection requirements, together with the essential descriptive parameters, limiting values, electrical characteristics and marking and ordering information which shall be included as mandatory requirements in any detail specification for these components.

Cross-references

Publication referred to	Corresponding British Standard
IEC 68-2-17:1978	BS 2011 <i>Environmental testing</i> Part 2.1 <i>Tests</i> Part 2.1Q:1981 <i>Test Q. Sealing</i>
IEC 617-12:1991	BS 3939 <i>Graphical symbols for electrical power, telecommunications and electronics diagrams</i> Part 12:1991 <i>Guide for binary logic elements</i>
IEC 747-10:1991	BS QC 700000:1991 <i>Harmonized system of quality assessment for electronic components. Generic specification for discrete devices and integrated circuits</i>
IEC 748-2:1985	BS 6493 <i>Semiconductor devices</i> Part 2 <i>Integrated circuits</i> Section 2.2:1986 <i>Recommendations for digital integrated circuits</i>
IEC 748-11:1990	BS QC 790100:1991 <i>Harmonized system of quality assessment for electronic components. Semiconductor devices. Sectional specification for semiconductor integrated circuits excluding hybrid circuits</i>
IEC 749:1984	BS 6493 <i>Semiconductor devices</i> Part 3:1985 <i>Mechanical and climatic test methods</i>

The British Standard which implements the IECQ Rules of Procedure is BS 9000 *General requirements for a system of electronic components of assessed quality — Part 3:1991 Specification for the national implementation of the IECQ System*.

Detail Specifications

Detail specifications shall comply with the requirements of this Blank Detail Specification and BS QC 001002:1991 *Rules of Procedure of the IEC Quality assessment System for Electronic Components (IECQ)*.

A British Standard does not purport to include all the necessary provisions of a contract. Users of British Standards are responsible for their correct application.

Compliance with a British Standard does not of itself confer immunity from legal obligations.

Summary of pages

This document comprises a front cover, an inside front cover, pages i to iv, the IEC title page, pages ii to iv, pages 1 to 15 and a back cover.

This standard has been updated (see copyright date) and may have had amendments incorporated. This will be indicated in the amendment table on the inside front cover.

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INTERNATIONAL
STANDARD**

**CEI
IEC
748-2-9**

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**Dispositifs à semiconducteurs –
Circuits intégrés –**

**Partie 2:
Circuits intégrés numériques –
Section 9: Spécification particulière cadre
pour les mémoires mortes MOS effaçables
aux UV et programmables électriquement**

**Semiconductor devices –
Integrated circuits –**

**Part 2:
Digital integrated circuits –
Section 9: Blank detail specification for MOS
ultraviolet light erasable electrically programmable
read-only memories**

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